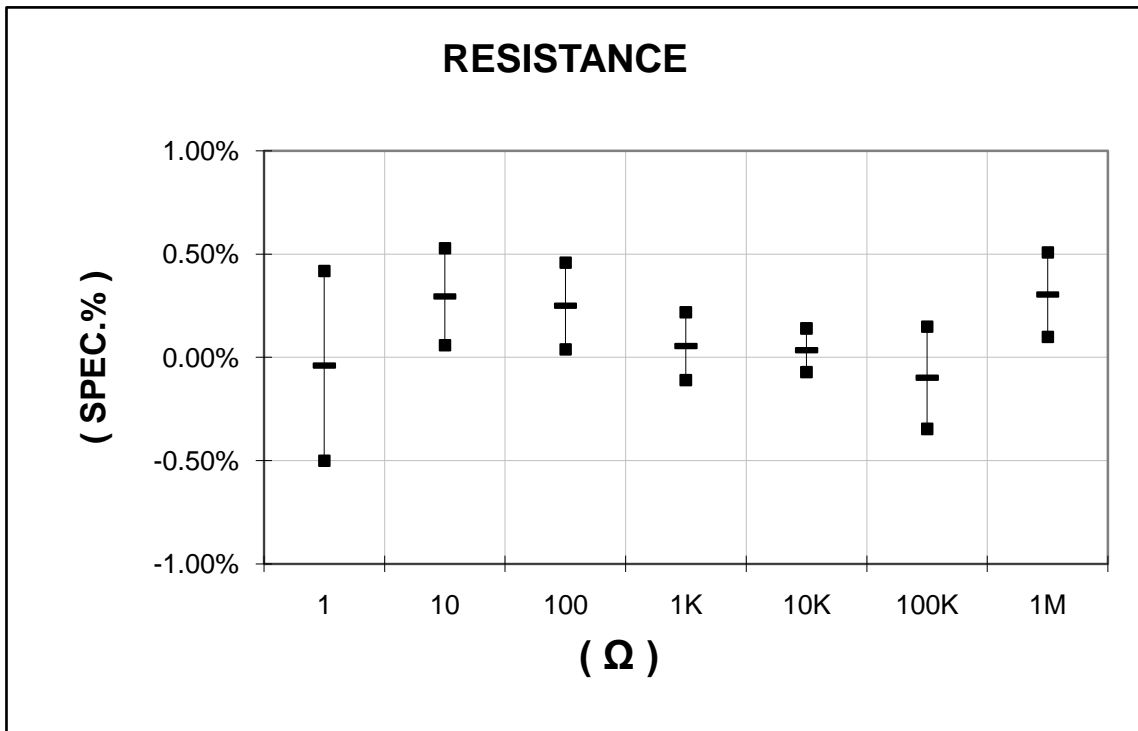




RELIABILITY TEST OF CHIP RESISTOR - 2010 - 1%

Test : Resistance
JIS C 5202 5.1
Test Equipment : Digital Multimeter 34420A
Digital Multimeter 34401A
Spec: ± 1 % (1 Ω ~ 1 MΩ)

Date of test completed: 07.11.2008



Sample size 10pcs per value



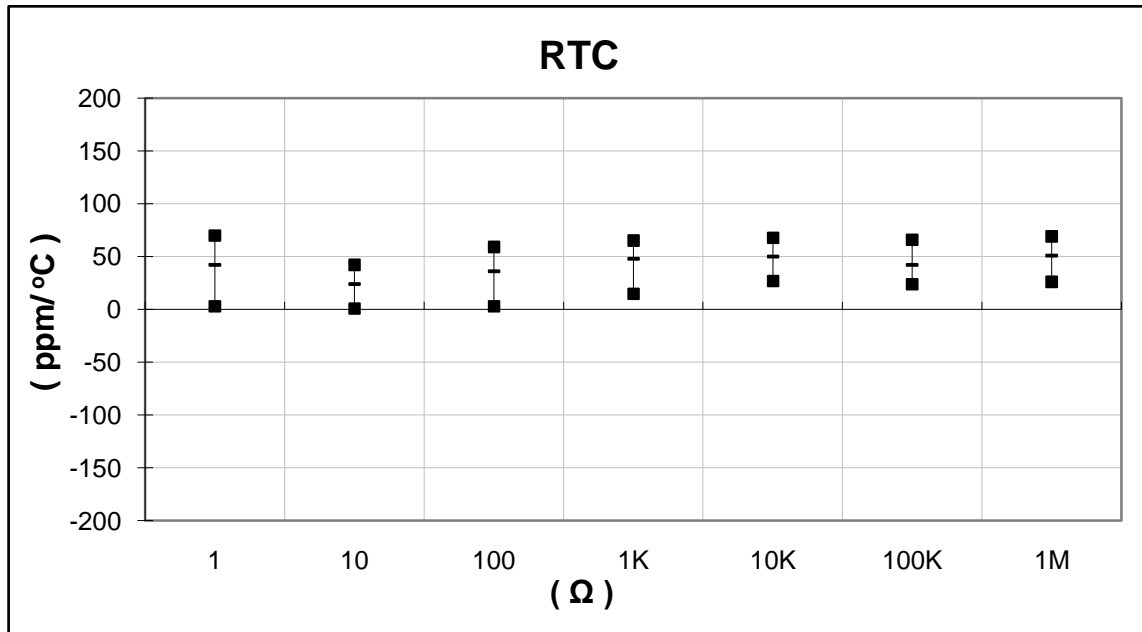
RELIABILITY TEST OF CHIP RESISTOR - 2010 - 1%

Test : Resistance Temperature of Coefficient
JIS C 5202 5.2

Date of test completed: 07.11.2008

Test Equipment : Delta Oven SE 369
Digital Multimeter 34420A
Digital Multimeter 34401A
Test temperature 125 °C ± 5°C keep
samples for 30 ~45 mins, then measure
the sample resistance at that temperature.

Spec: ± 200ppm/°C (1 Ω ≤ R < 10 Ω)
± 100ppm/°C (10 Ω ≤ R < 1 MΩ)



Sample size 10pcs per value



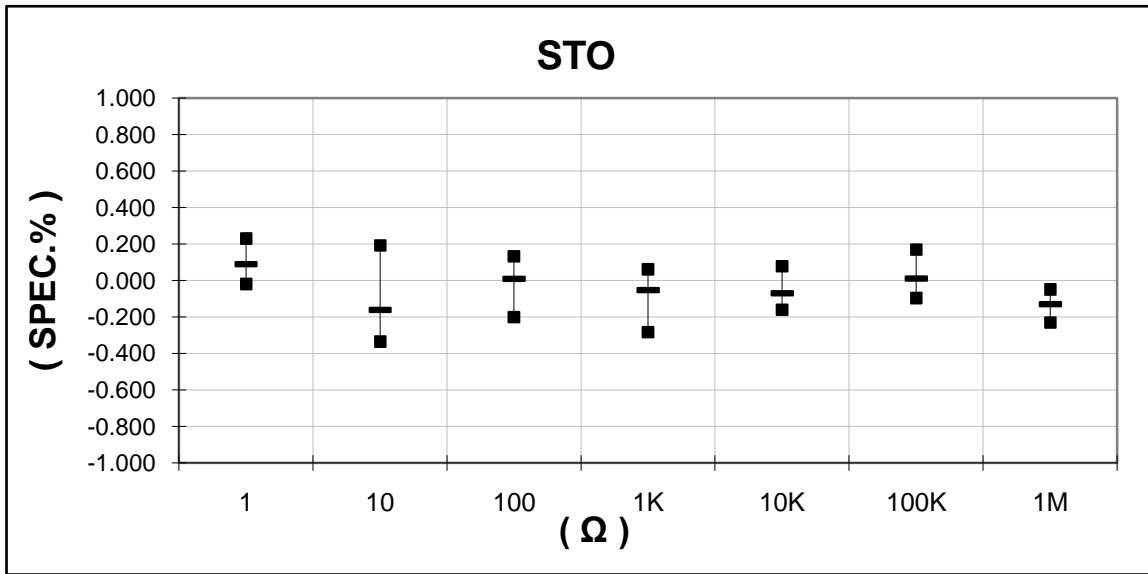
RELIABILITY TEST OF CHIP RESISTOR - 2010 - 1%

Test : Short Time Overload (STO)
JIS C 5202 5.5

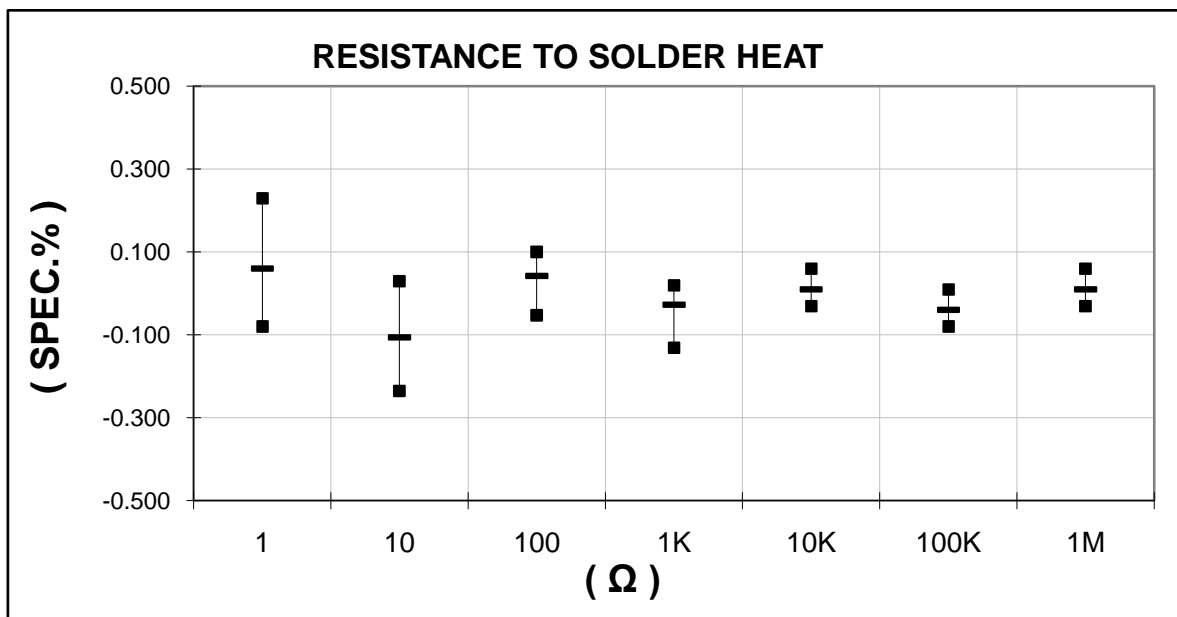
Date of test completed: 07.11.2008

Test Equipment : Digital Multimeter 34420A
Digital Multimeter 34401A
STO Tester
Measure the initial resistance.
Apply 2.5 times RCWV but not exceeding
twice the max voltage to sample for 5 secs.
Removed the voltage, leaves sample for 30 mins.
Then measure final resistance.

Spec: ± 1%



Sample size 10pcs per value

ASJ**RELIABILITY TEST OF CHIP RESISTOR - 2010 - 1%**Test : Resistance to Soldering HeatDate of test completed: 07.11.2008JIS C 5202 6.10Test Equipment : Digital Multimeter 34420ADigital Multimeter 34401ASolder Pot 260 °C ± 5 °Cfor 10 secs. ± 1sec.Leaves sample for 1~2 hrs thenmeasure the final resistance.Spec: ± 0.5 %

Sample size 10pcs per value



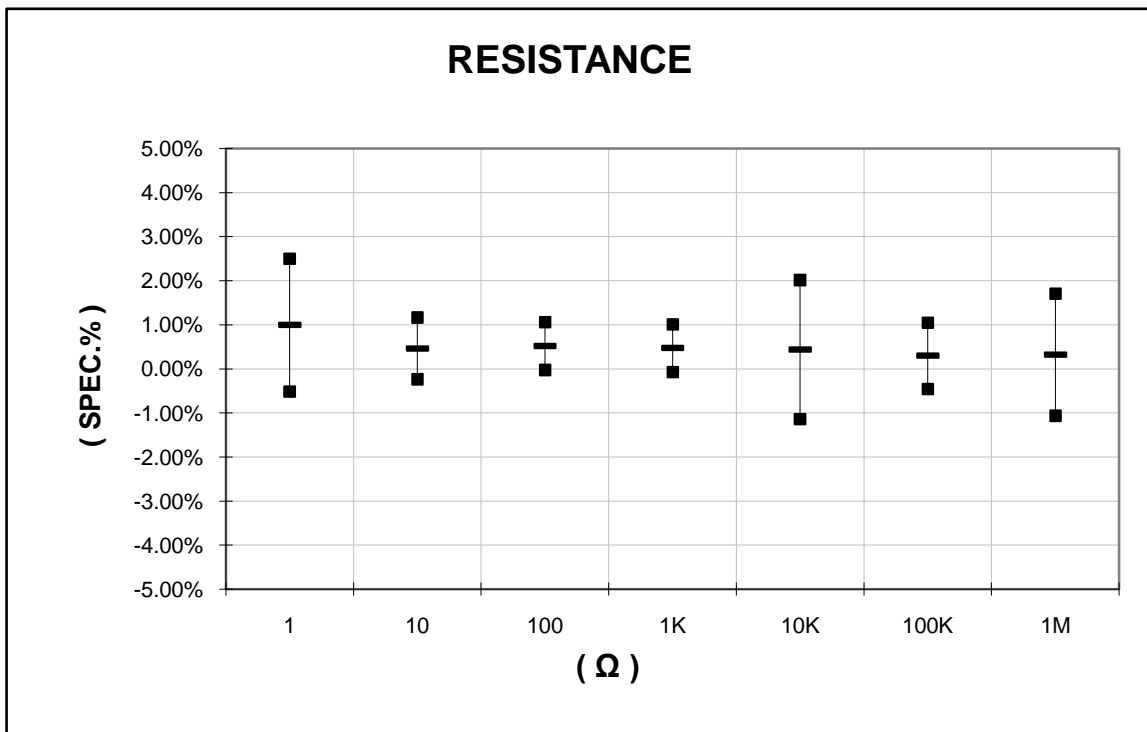
RELIABILITY TEST OF CHIP RESISTOR - 2010 - 5%

Test : Resistance
JIS C 5202 5.1

Test Equipment : Digital Multimeter 34420A
Digital Multimeter 34401A

Spec: ± 5 % (1 Ω ~ 1 MΩ)

Date of test completed: 07.11.2008



Sample size 10pcs per value



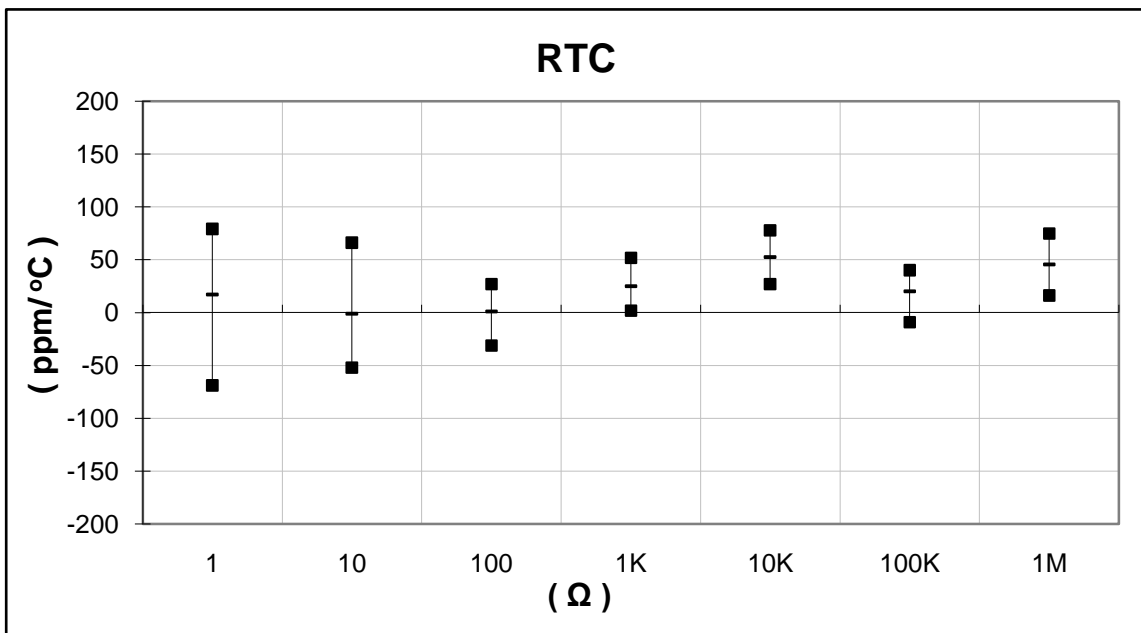
RELIABILITY TEST OF CHIP RESISTOR - 2010 - 5%

Test : ResistanceTemperature of Coefficient
JIS C 5202 5.2

Date of test completed: 07.11.2008

Test Equipment : Delta Oven SE 369
Digital Multimeter 34420A
Digital Multimeter 34401A
Test temperature 125 °C ± 5°C keep
samples for 30 ~45 mins,then measure
the sample reistance at that temperature.

Spec: -200ppm/°C to +300ppm/°C (1Ω ≤ R < 10Ω)
± 200ppm/°C (10Ω ≤ R < 1MΩ)



Sample size 10pcs per value



RELIABILITY TEST OF CHIP RESISTOR - 2010 - 5%

Test : Short Time Overload (STO)

Date of test completed: 07.11.2008

JIS C 5202 5.5

Test Equipment : Digital Multimeter 34420A

Digital Multimeter 34401A

STO Tester

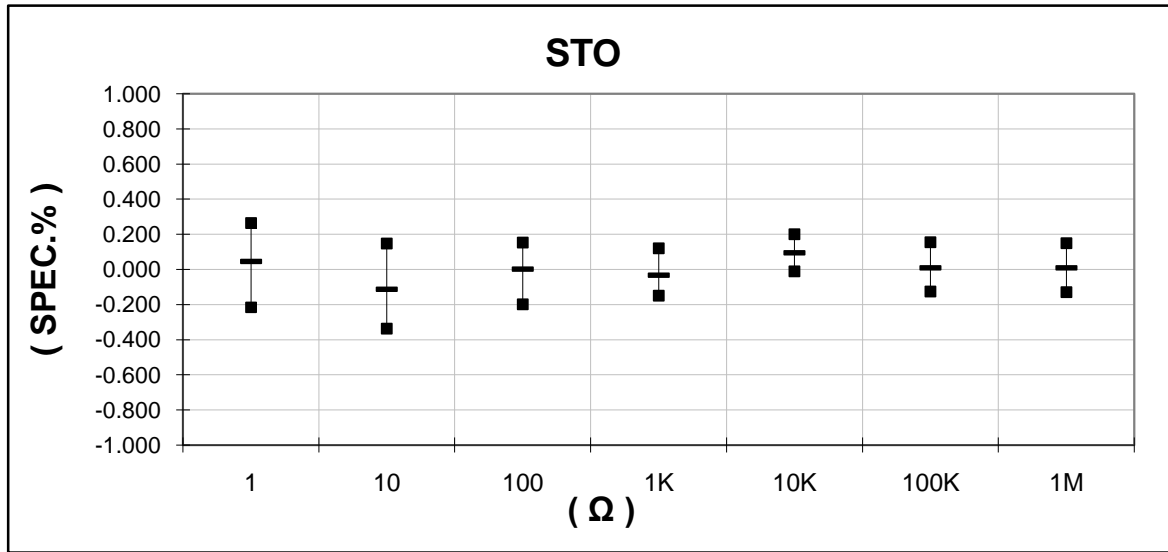
Measure the initial reistance.

Apply 2.5 times RCWV but not exeeding
twice the max voltage to sample for 5 secs.

Removed the voltage, leaves sample for 30 mins.

Then measure final resistance.

Spec: ± 1%



Sample size 10pcs per value



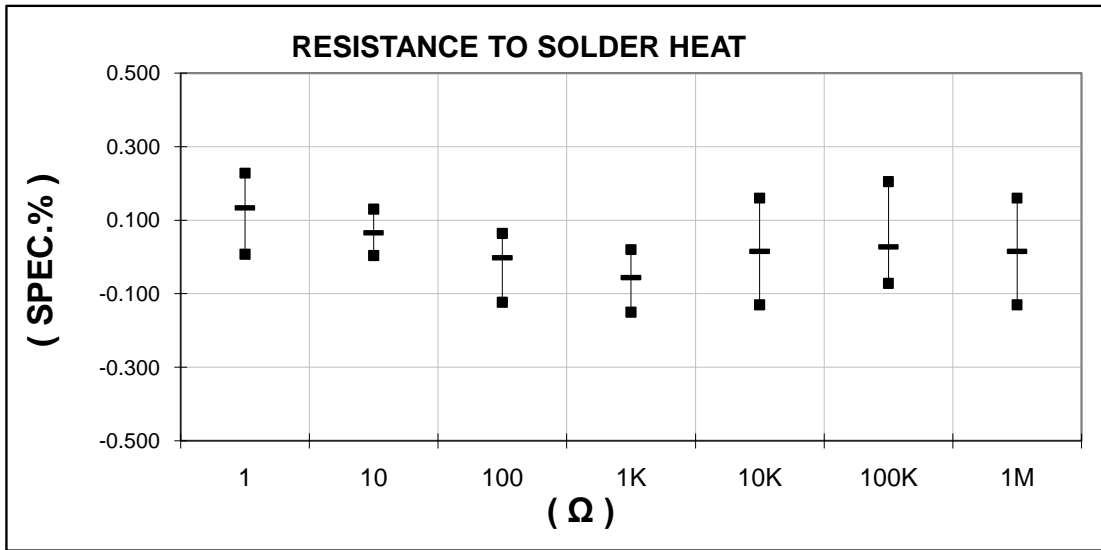
RELIABILITY TEST OF CHIP RESISTOR - 2010 - 5%

Test : Resistance to Soldering Heat
JIS C 5202 6.10

Test Equipment : Digital Multimeter 34420A
Digital Multimeter 34401A
Solder Pot 260 °C ± 5 °C
for 10 secs. ± 1sec.
Leaves sample for 1~2 hrs then
measure the final resistance.

Spec: 0.5 %

Date of test completed: 07.11.2008



Sample size 10pcs per value